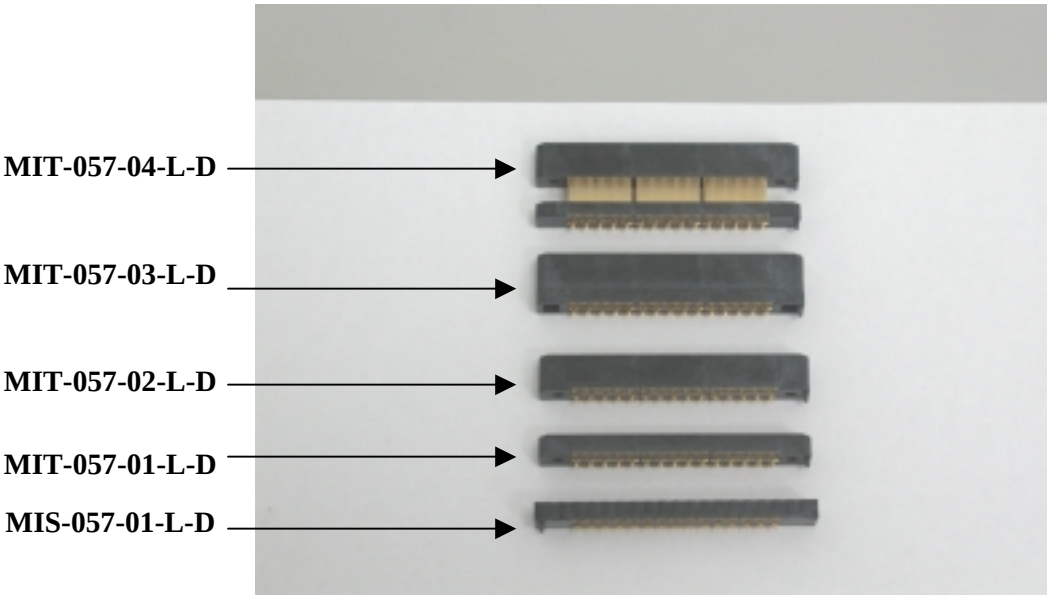
Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D		Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier
Part description: .635mm Double Row High Speed Connector Assembly			Qty to test: 4	
Test Start: 8/22/01	Test Completed: 9/20/01			



SUMMARY REPORT

PART DESCRIPTION

MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D

Testing Scope : CCC/IR/DWV

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D		Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier
Part description: .635mm Double Row High Speed Connector Assembly			Qty to test: 4	
Test Start: 8/22/01	Test Completed: 9/20/01			

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to IS0 10012-l and ANSI/NCSL 2540-1, as applicable.

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D	Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier	
Part description: .635mm Double Row High Speed Connector Assembly	Qty to test: 4			
Test Start: 8/22/01	Test Completed: 9/20/01			

SCOPE

To perform the following tests: CCC/IR/DWV

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

1) All materials were manufactured in accordance with the applicable product specification.
2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
3) After soldering, the parts to be used for LLCR testing were cleaned according to TLWI-0001:
   a) Sample test boards are to be ultrasonically cleaned after test lead attachment, preparation and/or soldering using the following process.
   b) Immerse the sample test boards into the Branson 3510 cleaner which contains Kyzen Ionox HC1 (or equivalent) cleaning solution with the following conditions:
      i) Temperature: 55 Degrees C+/- 5 Degrees C
      ii) Frequency: 40 KHz
      iii) Immersion Time: 5 to 10 Minutes
   c) Sample test boards are then slowly removed and placed into the Branson 3510 cleaner which contains DI water with the following conditions:
      i) Temperature: 55 Degrees C +/- 5 Degrees C
      ii) Frequency: 40 KHz
      iii) Immersion Time: 5 to 10 Minutes
   d) Sample test boards are then removed and placed in a a beaker, on a hot plate with a magnetic stirrer containing DI water warmed to 55 +/- 5 Degrees C for 1/2 to 1 minute (Use 55 C as target)
   e) Upon removal, the sample test boards are then rinsed for 1/2 to 1 minute in room temperature free flowing DI water.
   f) After the final rinse, the sample test boards are to be dried in an air-circulating oven for 10 to 15 minutes at 50 +/- 5 Degrees C (Use 50 C as target)
   g) Sample test boards are then allowed to set and recover to room ambient condition prior to testing.
4) Parts not intended to be tested for LLCR are visually inspected and cleaned if necessary.
5) Any additional preparation will be noted in the individual test procedures..

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
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Part description: .635mm Double Row High Speed Connector Assembly			Qty to test: 4	
Test Start: 8/22/01	Test Completed: 9/20/01			

FLOWCHART

GROUP 1 1 Boards 5 interdigitated contacts	GROUP 2A 1 Boards 10 Contacts in series	GROUP 2B 1 Boards 2 GP in series
IR	Temp Rise	Temp Rise
DWV		
Thermal Aging		
IR		
DWV		
Cyclic Humidity		
IR		
DWV		
W V		

Thermal Aging = EIA-364-17B Test Condition 5 at 125 deg C
Test Time Condition 'B' but for 300 hours
Cyclic Humidity =10 days with 1 cycles/day, +25 @ 92%RH to +65 @ 92%RH
(EIA-364-31A)
Temperature derated 20% and based on 125 deg C
Tabulate at RT, 60 and 80 degrees C

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D		Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier
Part description: .635mm Double Row High Speed Connector Assembly			Qty to test: 4	
Test Start: 8/22/01	Test Completed: 9/20/01			

ATTRIBUTE DEFINITION

Following is a brief, simplified description of each attribute measured.

THERMAL AGING

1) EIA-364-17B, *Temperature Life with or without Electrical Load Test Procedure for Electrical Connectors,* Test Condition 5 at 125 degrees C, Test Time Condition B but for 300 hours.
2) Connectors are mated.

CYCLIC HUMIDITY

1) Reference document: EIA-364-31A, *Humidity Test Procedure for Electrical Connectors*, Method III, Test Condition B excluding Steps 7a, 7b [10 days, +25 deg C to + 65 deg C, 90% to 95% RH].

TEMPERATURE RISE:

1) When current passes through a contact, the temperature of the contact increases as a result of I^2R (resistive) heating.
2) The number of contacts being investigated plays a significant part in power dissipation and therefore temperature rise.
3) The size of the temperature probe can affect the measured temperature.
4) Copper traces on PC boards will contribute to temperature rise:
   a) Self heating (resistive)
   b) Reduction in heat sink capacity affecting the heated contacts
5) EIA-364-70A, *Temperature Rise versus Current Test Procedure for Electrical Connectors and Sockets*.
6) A de-rating curve, usually 20%, is calculated.
7) Calculated de-rated currents at three temperature points are reported:
   a) Ambient
   b) 60^{o} C
   c) 80^{o} C
8) Typically, neighboring contacts (in close proximity to maximize heat build up) are energized.
9) The thermocouple (or temperature measuring probe) will be positioned at a location to sense the MAXIMUM temperature in the vicinity of the heat generation area.
10) A computer program, *TR 803.exe*, ensures accurate stability for data acquisition.
11) Hook-up wire cross section is larger than the cross section of any connector leads/PC board traces, jumpers, etc.
12) Hook-up wire length is longer than the minimum specified in the referencing standard.

DIELECTRIC WITHSTANDING VOLTAGE (DWV)

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon.

1) PROCEDURE:
   a) Reference document: EIA-364-20B, *Withstanding Voltage Test Procedure for Electrical Connectors*.

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D		Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier
Part description: .635mm Double Row High Speed Connector Assembly		Qty to test: 4		
Test Start: 8/22/01	Test Completed: 9/20/01			

b) Test Conditions:
   i) Between Adjacent Contacts
   ii) Mated or Unmated
   iii) Mounted or Unmounted
   iv) Rate of Application 500 V/Sec
   v) Test Voltage (VAC) until breakdown occurs

2) MEASUREMENTS/CALCULATIONS
   a) The breakdown voltage shall be measured and recorded.
   b) The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage
   c) .The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

INSULATION RESISTANCE (IR)

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

1) PROCEDURE:
   a) Reference document: EIA-364-21B, *Insulation Resistance Test Procedure for Electrical Connectors*.
   b) Test Conditions:
      i) Between Adjacent Contacts
      ii) Mated or Unmated
      iii) Mounted or Unmounted
      iv) Electrification Time 2.0 minutes
      v) Test Voltage (VDC) corresponding to calibration settings for measuring resistances
2) MEASUREMENTS:
   a) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 5000 megohms.

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D		Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier
Part description: .635mm Double Row High Speed Connector Assembly			Qty to test: 4	
Test Start: 8/22/01	Test Completed: 9/20/01			

TEST PROCEDURES / RESULTS

TEMPERATURE RISE:

1) High quality thermocouples whose temperature slopes track one another were used for temperature monitoring.
2) The thermocouples were placed at a location to sense the MAXIMUM temperature generated during testing.
3) Temperature readings recorded are those for which three successive readings, 15 minutes apart, differ less than 1 degree (computer controlled data acquisition).

DATA SUMMARY

- All test data is summarized in the following table. Only one set of derated curves for the samples is depicted. These curves represent the 'worst case' in that the highest temperature was detected in the respective tests (GP and Contact)

Three Ground Planes in Series - Indicated Temp Rise, deg C

Current, DC A	-01 Height	-02 Height	-03 Height	-04 Height
0	0	0	0	0
1.6	0.9	0.9	0.6	0.3
3.2	3.3	3.7	2.8	2.6
4.8	7.2	8.5	6.3	6.1
6.4	12.8	15.3	11.2	11.0
8.0	20.2	24.1	17.4	17.2

Ten Contacts in Series - Indicated Temp Rise, deg C

Current, DC A	-01 Height	-02 Height	-03 Height	-04 Height
0	0	0	0	0
0.4	1.2	1.7	2.0	1.3
0.8	5.0	7.2	7.4	5.6
1.2	11.1	16.2	16.3	12.8
1.6	19.9	28.8	28.8	21.9
2.0	31.8	45.3	45.2	33.1

Project Number: 027C	Tracking Code: 0133-027C-0497			
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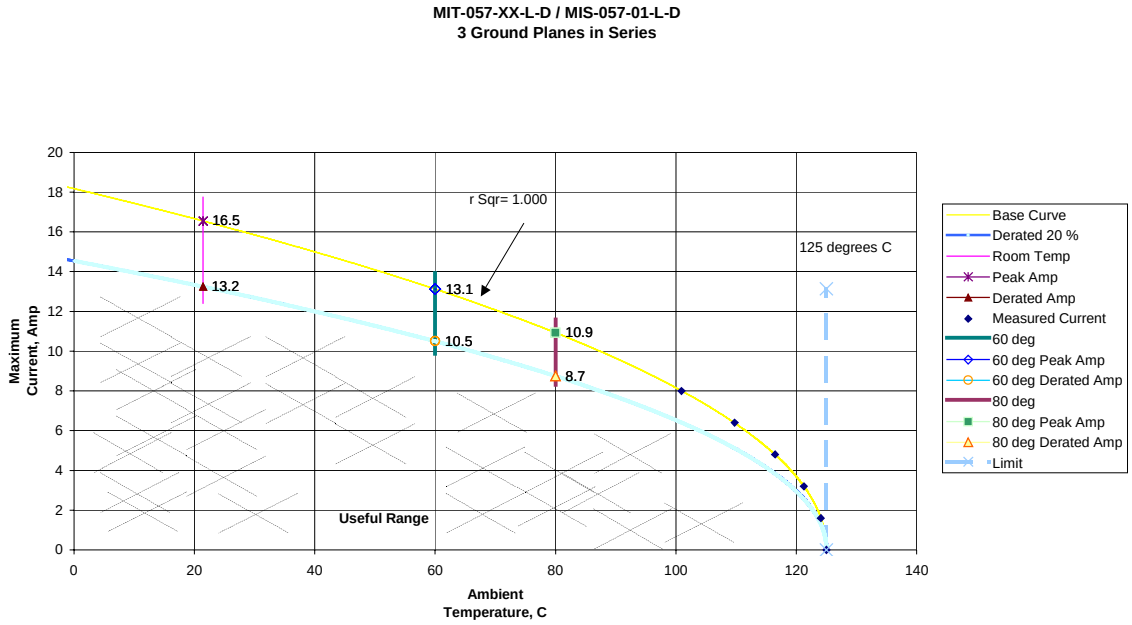
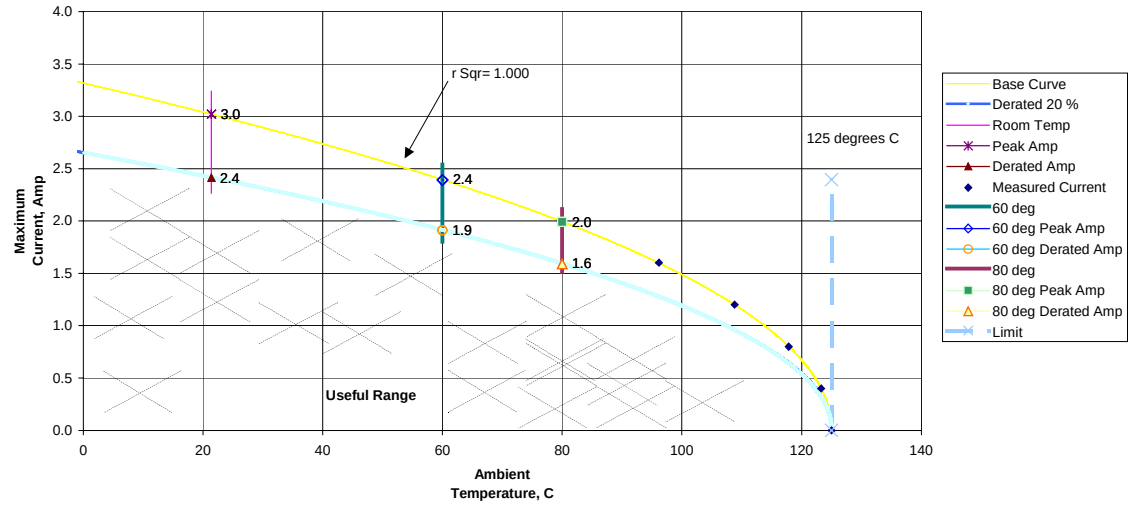
Part description: .635mm Double Row High Speed Connector Assembly		Qty to test: 4		
Test Start: 8/22/01	Test Completed: 9/20/01			

GROUND PLANE TEMPERATURE RISE



CONTACT TEMPERATURE RISE



Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D	Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier	
Part description: .635mm Double Row High Speed Connector Assembly	Qty to test: 4			
Test Start: 8/22/01	Test Completed: 9/20/01			

DIELECTRIC WITHSTANDING VOLTAGE (DWV)

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon.

1) PROCEDURE:
   a) Reference document: EIA-364-20B, *Withstanding Voltage Test Procedure for Electrical Connectors*.
2) MEASUREMENTS/CALCULATIONS
   a) The breakdown voltage shall be measured and recorded.
   b) The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage.
   c) The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

Series Contact is Used In: MIS
Series Contact Mates With: MIT

Test Conditions	**YES**	**NO**
Between Adjacent Contacts	X	
Mated	X	
PC Mounted	X	

Rate Of Applied Voltage *500 V Per Sec.*
Test Voltage *Until Breakdown Occurrs*

Values in VDC

Sample #	**Breakdown Voltage 8/22/01 Initial**	**Breakdown Voltage 9/10/01 After Thermal**	**Breakdown Voltage 9/20/01 After Humidity**	**DWV 8/22/01 Initial**	**DWV 9/10/01 After Thermal**	**DWV 9/20/01 After Humidity**	**Working Voltage 8/22/01 Initial**	**Working Voltage 9/10/01 After Thermal**	**Working Voltage 9/20/01 After Humidity**
Average	1300	1288	1298	NA	NA	NA	NA	NA	NA
Min	1200	1200	1140	900	900	855	300	300	285
Max	1350	1350	1400	NA	NA	NA	NA	NA	NA

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D		Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier
Part description: .635mm Double Row High Speed Connector Assembly			Qty to test: 4	
Test Start: 8/22/01	Test Completed: 9/20/01			

INSULATION RESISTANCE (IR)

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

1) PROCEDURE:
   a) Reference document: EIA-364-21B, *Insulation Resistance Test Procedure for Electrical Connectors*.

2) MEASUREMENTS:
   a) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 5000 megohms

Series Contact is Used In: MIS
Series Contact Mates With: MIT

Test Conditions	**YES**	**NO**
Between Adjacent	**X**	
Mated	**X**	
PC Mounted	**X**	

Electrification Time *Two (2) minutes*

Values in Mohms

Sample #	**Insulation Resistance 8/22/01 Initial**	**Insulation Resistance 9/10/01 After Thermal**	**Insulation Resistance 9/20/01 After Humidity**
Average	87500	87500	87500
Min	50000	50000	50000
Max	100000	100000	100000

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D	Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier	
Part description: .635mm Double Row High Speed Connector Assembly	Qty to test: 4			
Test Start: 8/22/01	Test Completed: 9/20/01			

DATA DWV
INITIAL

Test Date:	Initial	8/22/2001
Operator:		TC
Temperature (C):		23
Humidity (RH):		41%
Pressure (In. Hg):		29.44
Equipment Code Number		3

Contact Description

1. Contact Part #:

2. Series Contact is Used In: MIS

3. Series Contact Mates With: MIT

Test Conditions	**YES**	**NO**
Between Adjacent Contacts	X	
Mated	X	
PC Mounted	X	

Rate Of Applied Voltage *500 V Per Sec.*

Test Voltage *Until Breakdown Occurs*

Values in VDC

Board/Sample #	**Breakdown Voltage**
1	1200
2	1300
3	1350
4	1350

Average	1300
Min	1200
Max	1350

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D		Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier
Part description: .635mm Double Row High Speed Connector Assembly			Qty to test: 4	
Test Start: 8/22/01	Test Completed: 9/20/01			

DATA DWV
AFTER THERMAL

	After Thermal
Test Date:	9/10/2001
Operator:	TC
Temperature (C):	23
Humidity (RH):	53%
Pressure (In. Hg):	N/A
Equipment Code Number	3

Contact Description

Series Contact is Used In: MIS

Series Contact Mates With: MIT

Test Conditions	**YES**	**NO**
Between Adjacent Contacts	X	
Mated	X	
PC Mounted	X	

Rate Of Applied Voltage *500 V Per Sec.*

Test Voltage *Until Breakdown Occurs*

Values in VDC

Board/Sample #	**Breakdown Voltage**
1	1200
2	1300
3	1300
4	1350

Average	1288
Min	1200
Max	1350

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
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Test Start: 8/22/01	Test Completed: 9/20/01			

DATA DWV
AFTER HUMIDITY

	After Humidity
Test Date:	9/20/2001
Operator:	TC
Temperature (C):	23
Humidity (RH):	35%
Pressure (In. Hg):	29.42
Equipment Code Number	3

Contact Description

Series Contact is Used In: MIS

Series Contact Mates With: MIT

Test Conditions	**YES**	**NO**
Between Adjacent Contacts	X	
Mated	X	
PC Mounted	X	

Rate Of Applied Voltage *500 V Per Sec.*

Test Voltage *Until Breakdown Occurs*

Values in VDC

Board/Sample #	**Breakdown Voltage**
1	1140
2	1350
3	1400
4	1300

Average	1298
Min	1140
Max	1400

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D	Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier	
Part description: .635mm Double Row High Speed Connector Assembly	Qty to test: 4			
Test Start: 8/22/01	Test Completed: 9/20/01			

DATA IR
INITIAL

Test Date:	Initial	8/22/2001
Operator:		TC
Temperature (C):		23
Humidity (RH):		41%
Pressure (In. Hg):		29.44
Equipment Code Number		3

Contact Description
Series Contact is Used In: MIS
Series Contact Mates With: MIT

Test Conditions	**YES**	**NO**
Between Adjacent Contacts	**X**	
Mated	**X**	
PC Mounted	**X**	

Electrification Time *Two (2) minutes*

Values in Mohms

Board/Sample #	**Insulation Resistance**
1	50000
2	100000
3	100000
4	100000

Average	87500
Min	50000
Max	100000

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D		Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier
Part description: .635mm Double Row High Speed Connector Assembly			Qty to test: 4	
Test Start: 8/22/01	Test Completed: 9/20/01			

DATA IR
AFTER THERMAL

	After Thermal
Test Date:	9/10/2001
Operator:	TC
Temperature (C):	23
Humidity (RH):	54%
Pressure (In. Hg):	N/A
Equipment Code Number	3

Contact Description
Series Contact is Used In: MIS
Series Contact Mates With: MIT

Test Conditions	**YES**	**NO**
Between Adjacent Contacts	**X**	
Mated	**X**	
PC Mounted	**X**	

Electrification Time *Two (2) minutes*

Values in Mohms

Board/Sample #	**Insulation Resistance**
1	100000
2	50000
3	100000
4	100000

Average	87500
Min	50000
Max	100000

DATA IR

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D		Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier
Part description: .635mm Double Row High Speed Connector Assembly			Qty to test: 4	
Test Start: 8/22/01	Test Completed: 9/20/01			

AFTER HUMIDITY

	After Humidity
Test Date:	9/20/2001
Operator:	TC
Temperature (C):	23
Humidity (RH):	36%
Pressure (In. Hg):	29.42
Equipment Code Number	3

Contact Description

Series Contact is Used In: MIS

Series Contact Mates With: MIT

Test Conditions	**YES**	**NO**
Between Adjacent Contacts	**X**	
Mated	**X**	
PC Mounted	**X**	

Electrification Time *Two (2) minutes*

Values in Mohms

Board/Sample #	**Insulation Resistance**
1	100000
2	100000
3	100000
4	50000

Average	87500
Min	50000
Max	100000

EQUIPMENT AND CALIBRATION SCHEDULES

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D		Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier
Part description: .635mm Double Row High Speed Connector Assembly		Qty to test: 4		
Test Start: 8/22/01	Test Completed: 9/20/01			

Description: Temperature/Humidity Chart Recorder
Manufacturer: Dickson
Model: THDX
Serial #: 9316255
Accuracy: Temp: +/- 1C; Humidity: +/-2% RH (0 - 60%) +/- 3% RH (61 - 95%).
… Last Cal: 6/15/01, Next Cal: 6/15/02

Description: Digital Thermometer
Manufacturer: Barnant 90
Model: 600-2840
Serial #: 621994
Accuracy: .25% reading +/- 1.0 degree Celsius
… Last Cal: 6/25/01, Next Cal: 6/25/02

Description: System Power Supply
Manufacturer: Hewlett Packard
Model: HP 6033A
Serial #: (HP) 3329A-07330
Accuracy: See Manual
… Last Cal: 6/14/01, Next Cal: 6/14/02

Description: Multimeter /Data Acquisition System
Manufacturer: Keithley
Model: 2700
Serial #: 0780546
Accuracy: See Manual
… Last Cal: 6/14/01, Next Cal: 6/14/02

Description: Hipot Megommeter
Manufacturer: Hipotronics
Model: H306B-A
Serial #: M9905004
Accuracy: 2 % Full Scale Accuracy
… Last Cal: 6/14/01, Next Cal: 6/14/02

Project Number: 027C	Tracking Code: 0133-027C-0497			
Requested by: W. OUYANG	Date: 8/16/01	Product Rev: B/A respectively		
Part #: MIT-057-01-L-D, MIT-057-02-L-D, MIT-057-03-L-D, MIT-057-04-L-D, MIS-057-01-L-D		Lot #: 08/15/01	Tech: T. Cook	Eng: J. Tozier
Part description: .635mm Double Row High Speed Connector Assembly			Qty to test: 4	
Test Start: 8/22/01	Test Completed: 9/20/01			

Description: Temperature/Humidity Chamber
Manufacturer: Thermotron
Model: SE-1000-6-6
Serial #: 31808
Accuracy: see manual
… Last Cal: 3/27/01, Next Cal: 3/27/02

Description: Temperature/Humidity Chamber
Manufacturer: Thermotron
Model: SM-8-7800
Serial #: 30676
Accuracy: see manual
… Last Cal: 6/14/01, Next Cal: 6/30/02